# FORM PTO-1449 (MODIFIED)

# LIST OF PATENTS AND PUBLICATIONS FOR APPLICANTS INFORMATION DISCLOSURE STATEMENT

ATTORNEY DOCKET NO. SP01-300

SERIAL NO.

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APPLICANT Filhaber et al.

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MRCC	AA	5,915,193	6/22/99	Tong et al.	438	455				
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MRCC	AC	5,932,048	8/3/99	Furukawa et al.	156	153				
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mra	AE	6,153,495	11/28/00	Kub et al.	438	459				
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mpec	AO		A. Sayah, D. Solignac, T. Cueni, "Development of novel low temperature bonding technologies for microchip chemical analysis applications," Sensors and Actuators, 84 (2000) pp. 103-108.							
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# LIST OF PATENTS AND PUBLICATIONS FOR APPLICANTS INFORMATION DISCLOSURE STATEMENT

ATTORNEY DOCKET NO.

SERIAL NO.

SP01-300

10/035,358

APPLICANT Filhaber et al.

FILING DATE October 26, 2001

GROUP: To Be

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# REFERENCE DESIGNATION

#### U.S. PATENT DOCUMENTS

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SERIAL NO.

PUBLICATIONS
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SP01-300

ATTORNEY DOCKET NO.

10/035358

DISCLOSURE STATEMENT RADITLICANT : Filhaber, John F., et al.

FILING DATE 10/26/2001

**GROUP: 2874** 

#### REFERENCE DESIGNATION

#### U.S. PATENT DOCUMENTS

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m	AA	4,186,999	2/5/80	Harwood et al	350	96.21	10/25/77
mc	AB	4,407,667	10/4/83	Le Noane et al	65	3.11	7/20/81
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MC	AG	5,452,122	9/19/95	Tsuneda et al	359	281	8/5/91
mc	AH	5,785,874	7/28/98	Eda	216	24	8/4/95
mc	AI	5,852,622	12/22/98	Meissner et al	372	39	9/11/96
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mc	AV	DE19731075	1/21/99	Germany	03	29/00		X
mc	AW	WO01/98225	12/27/01	PCT	03	27/06	X	
MC	AX	WO01/73831	10/4/01	PCT .	01	21/304	<u> </u>	X
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ma	AZ	EP1057793	3/13/02	Europe	03	37/027	X	

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FOR APPLICANTS INFORMATION DISCLOSURE STATEMENT	APPLICANT: Filhaber, John F., et al.			
_	FILING DATE 10/26/2001	GROUP: 2874		

OTHER ART (Including Author, Title, Date, Pertinent Pages, etc.) Arthur Landrock. "Adhesives Technology Handbook." 1985, p. 117-118. BA BB Yoshikawa Hiroki; Japanese abstract of 2002321947; 11/8/02 "Optical Device and Method for Producing the Same" Furukata; Japanese Abstract of Publication No. 08146351; 6/7/96; "Element for Optical BC Isolator and its Production" BD Ohashi et al; Japanese Abstract of Publication No. 03-115178; 5/16/91; "Method for MC Joining Aluminum or Aluminum Ceramics by Diffusion". Onishi et al; "A Novel Temperature Compensation Method for SAW Devices Using BE MC Direct Bonding Techniques"; IEEE Ultrasonics Symposium; 1997; pages 227-230. AW **EXAMINER:** 

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